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Paper No. 16

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OFFICE OF PETITIONS

In re Application of :  
Birgit Schleifenbaum et al :  
Application No. 09/707,270 : ON PETITION  
Filed: November 6, 2000 :  
Attorney Docket No. Mo-5666/HR-231 :

This is a decision on the petition under 37 CFR 1.137(b), filed August 9, 2004, to revive the above-identified application.


The petition is **GRANTED**.

The above-identified application became abandoned for failure to reply within the meaning of 37 CFR 1.113 in a timely manner to the final Office action mailed November 27, 2002, which set a shortened statutory period for reply of three (3) months. A reply under 37 CFR 1.113 is limited to an amendment that *prima facie* places the application in condition for allowance or a Notice of Appeal (and appeal fee required by 37 CFR 1.17(b)). The reply submitted on April 3, 2003 did not *prima facie* place the application in condition for allowance as noted in the Advisory Action mailed April 24, 2003. Therefore, as no Notice of Appeal (and appeal fee), Request for Continued Examination (RCE) or a continuing application was timely filed. A one (1) month extension of time under the provisions of 37 CFR 1.136(a) were obtained. Accordingly, the above-identified application became abandoned on March 28, 2003.

The above-identified application is being revived for consideration of a submission under 37 CFR 1.114 (request for continued examination).

Telephone inquiries concerning this decision should be directed to Wan Laymon at (703) 305-9282.

This file is being forwarded to Technology Center AU 1761 for processing of the request for continued examination (RCE) under 37 CFR 1.114.

  
Wan Laymon  
Petitions Examiner  
Office of Petitions  
Office of the Deputy Commissioner  
for Patent Examination Policy